Search Notes



Application/Control N	Ο.
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Reexamination
LEE ET AL.

Applicant(s)/Patent Under

Examiner

Art Unit

Mui, Christine T

1709

SEARCHED

Class	Subclass	Date	Examiner
204	450	07.11.2007	CTM
366	341	07.11.2007	CTM
422	100, 101	07.11.2007	CTM
435	287.3	07.11.2007	CTM
436	052	07.11.2007	CTM
516	073	07.30.2007	CTM

SEARCH NOT	ES	3
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Search Notes	Date	Examiner
See EAST Search Report	07.10.2007	CTM
See Updated EAST Search Report	07 April 2008	CTM

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

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